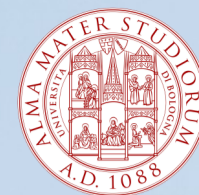




EXRS 2014

European Conference on X-Ray Spectrometry



Bologna (Italy), 15-20 June 2014

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Selected contributions will be published in the scientific journal **X-Ray Spectrometry**



<http://exrs2014.ing.unibo.it>

Topics

- Interactions of X-rays with matter and fundamental parameters
- XRS Instrumentation (X-ray sources, optics and detectors)
- Quantification methodology and metrology
- TXRF, GIXRF and related techniques
- Microbeam techniques, confocal XRF and XAFS
- Mobile and portable XRF
- XAFS, high resolution XES, synchrotron XRS and RIXS
- PIXE and electron induced XRS
- WDXRS
- X-ray imaging and tomography
- XRS applications:
 - Advanced materials and nanoscience
 - Art and cultural heritage
 - Earth and environment sciences
 - Industrial quality and process control
 - Life sciences and forensics
- Recent scientific developments by XRS instrumentation manufacturers

Invited speakers

John L. (Iain) Campbell, University of Guelph, Canada
Chris Chantler, University of Melbourne, Australia
Jose Maria Fernandez-Varea, University of Barcelona, Spain
Mauro Guerra, University of Lisbon, Portugal
Richard Hugtenburg, Swansea University, UK
Koen Janssens, University of Antwerp, Belgium
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Kenji Sakurai, National Institute for Materials Science, Japan
Dimosthenis Sokaras, SSRL - SLAC, USA
Laszlo Vincze, Ghent University, Belgium
Ziyu Wu, National Synchrotron Radiation Laboratory, China

Deadlines for Early Registration **May 15th, 2014** and Abstract submission **April 15th, 2014**